

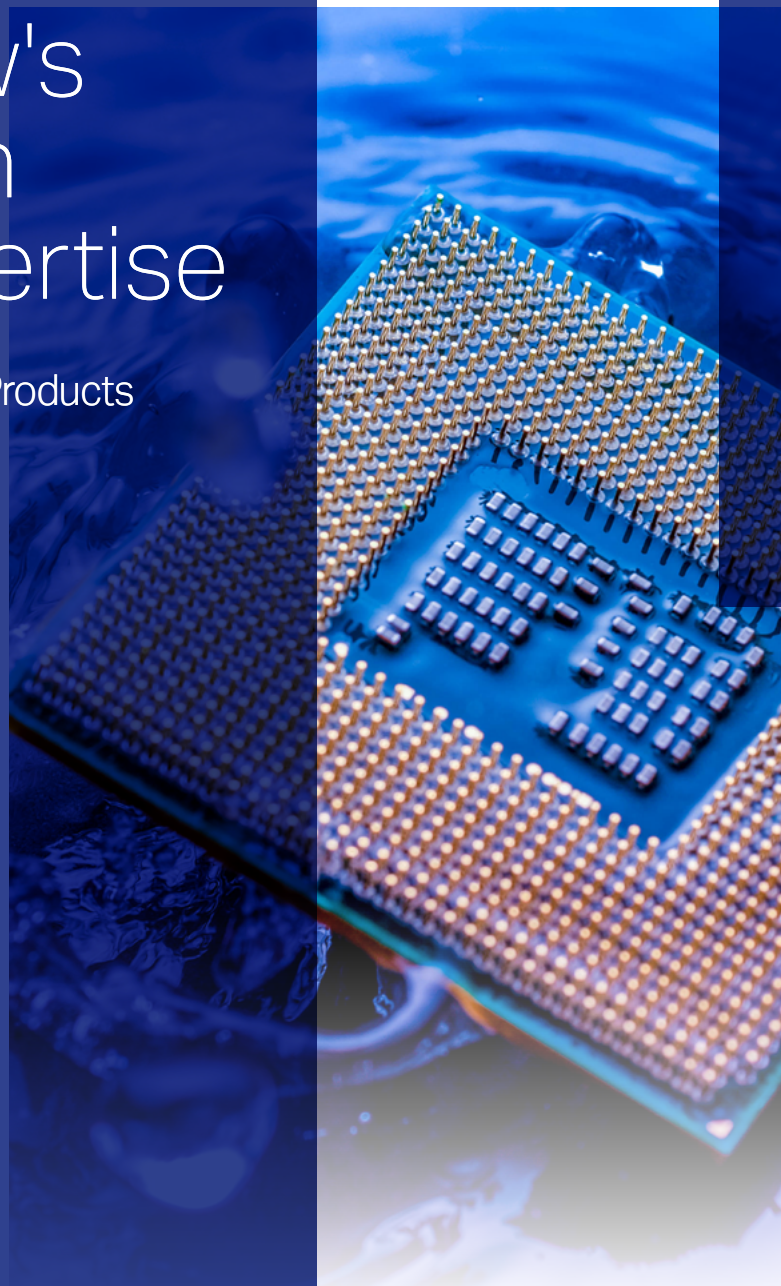
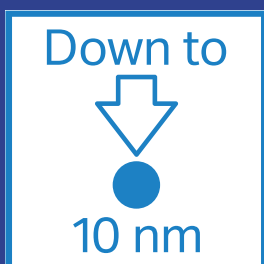


® Knowledge  
Beyond  
Measure.



# Meet Tomorrow's Challenges with Nanoscale Expertise

Particle and Environmental Monitoring Products  
for Electronics and Semiconductor



# Meet Tomorrow's Challenges with Nanoscale Expertise

## Environmental Monitoring Products for Electronics and Semiconductor

### Airborne Particle Counters

10 nm to 25 µm measurement

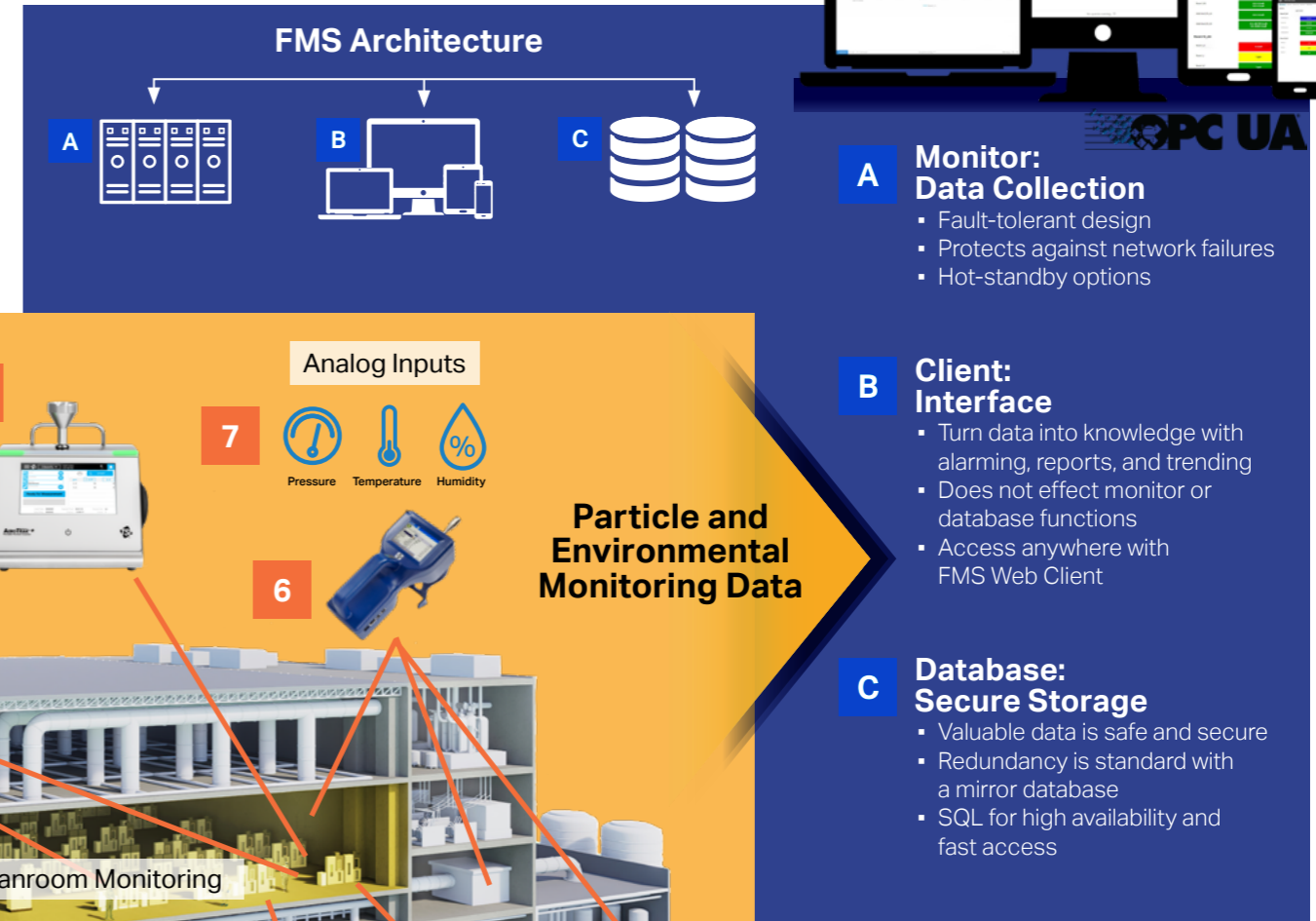
Models for every electronics and semiconductor environment and application including:

- Cleanroom monitoring
- Tool monitoring
- Gas monitoring

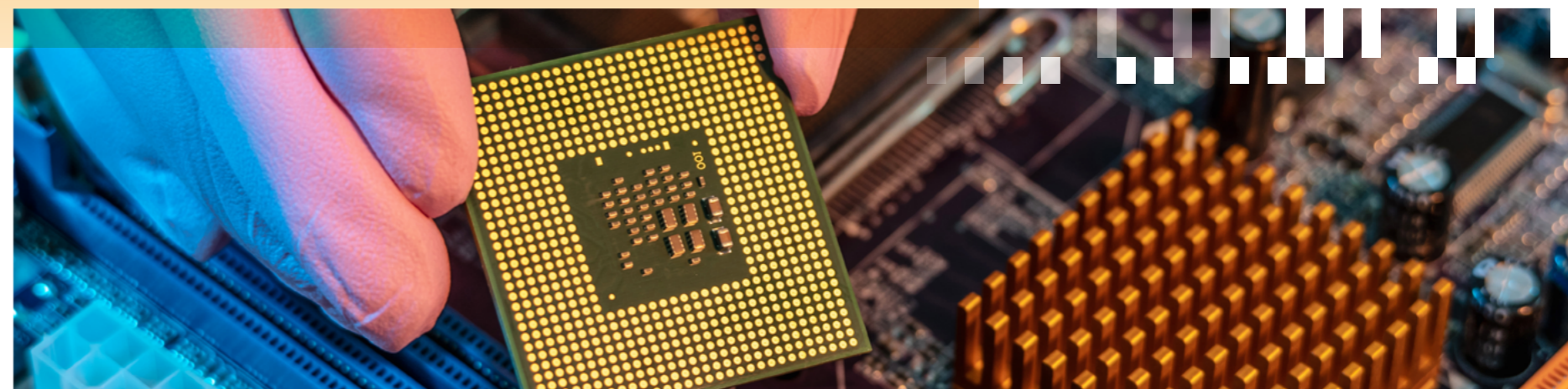
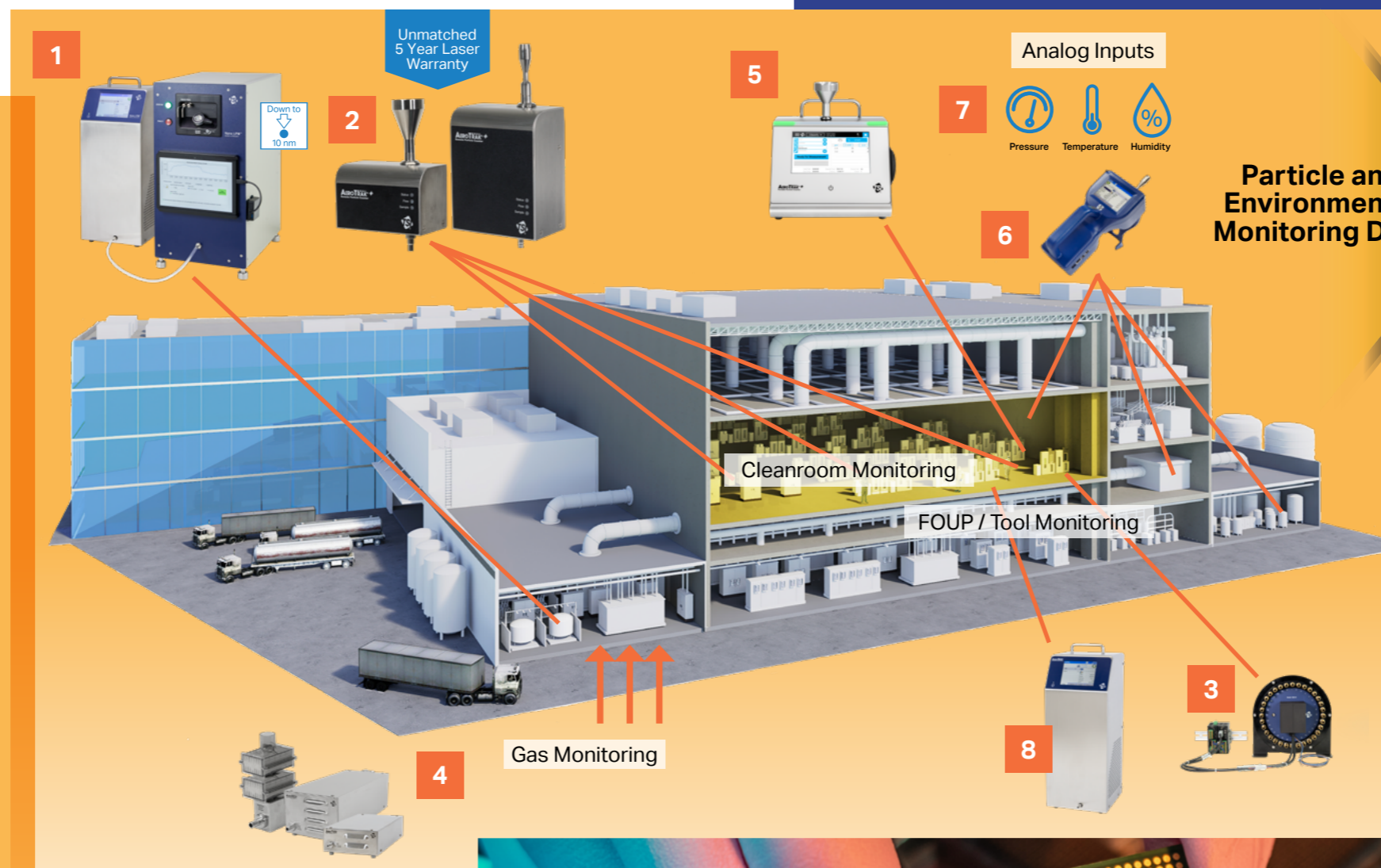
### TSI® Facility Monitoring Software: Reliable Monitoring Systems

**Distributed. Flexible. Redundant.**

- No single point of failure
- Data available where and when you need it
- Easily scalable



- 1 Nano LPM™ System**
  - Ensures reliable nanoparticle detection down to 10 nm in UPW
  - Ultralow false counts
  - Onboard tablet interface for modern, multi-functional data analysis
- 2 AeroTrak™+ Remote Particle Counters**  
**Ultra-Reliable Data Collection**
  - Protect against network failures with six months of data storage
  - Flexible environmental monitoring system with Wi-Fi® communication
- 3 Aerosol Sampling Manifold**
  - Monitor up to 32 points with a single particle counter
- 4 High Pressure Diffusers**
  - Measure particulate contamination in high-pressure compressed gas systems
- 5 AeroTrak™+ Portable Particle Counters**
  - Different sample modes for monitoring, classifying, and root cause investigation
  - Built-in monitoring and classification reports
- 6 AeroTrak™ Handheld Particle Counters**
- 7 Integrated Environmental Monitoring Probes**
  - Using FMS
- 8 AeroTrak™ Cleanroom Condensation Particle Counter**
  - Confident 24/7 operation
  - Minimal maintenance
  - High flow rates
  - Ultra-low false count rates
  - No contamination or chemicals introduced into the ultra-clean environment



# Meet Tomorrow's Challenges with Nanoscale Expertise

## Particle and Environmental Monitoring Products for Electronics and Semiconductor

### Facility Monitoring System

A reliable monitoring system that supports process control and decreases downtime.

Model	Flow Rate	Benefits and Features
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### Remote Particle Counters

Designed for continuous monitoring as part of the Facility Monitoring System with Analog and WiFi options

AeroTrak™+ 6000 series	0.1 CFM (2.83 LPM)	Measure down to 0.2 or up to 25 µm, includes onboard pump, compact size, many communications options
AeroTrak™+ 7000 series	0.1 CFM (2.83 LPM) & 1 CFM (28.3 LPM)	Measure down to 0.2 or up to 25 µm, compact size, many communications options
AeroTrak™+ 6310	1 CFM (28.3 LPM)	Full 1 CFM flow rate, 0.3 to 5.0 channels available, field-removable sensor/pump
AeroTrak™ 7110	1 CFM (28.3 LPM)	Accurately measures particles down to 0.1 µm, complies with all requirements of ISO 21501-4

### Portable Particle Counters

Versatile instruments suitable for classification and monitoring

AeroTrak™+ A100 Series	1 CFM (28.3 LPM), 1.77 CFM (50 LPM), and 3.53 CFM (100 LPM) models available	Intuitive interface, simplifies sampling with workflows, built-in classification and monitoring reporting capabilities, gas and filter testing
AeroTrak™ 9110	1 CFM (28.3 LPM)	Accurately measures particles down to 0.1 µm, includes display & onboard pump, provides classification testing, complies with all requirements of ISO 21501-4

### Handheld Particle Counters

Economical choice for higher class cleanrooms and investigations

AeroTrak™ 9303	0.1 CFM (2.83 LPM)	Small and lightweight, low cost and versatile
AeroTrak™ 9306	0.1 CFM (2.83 LPM)	Versatile, user-selectable channel version available

### Cleanroom Condensation Particle Counter

The only water-based, laminar flow CPC on the market that can run continuously, 24/7, or as a standalone unit

AeroTrak Cleanroom CPC 9001	0.1 CFM (2.83 LPM)	Measures down to 10 nm, ultralow zero counts for cleanroom processes
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### Nanoparticle Monitoring in Ultrapure Water

Empowers data-driven decisions in UPW monitoring...like never before.

Nano LPM™ System	12 mL/hour (±2 mL) (Water Sample)	Enables proactive, data-driven action before product quality is affected — ensuring reliable detection down to 10 nm, ultralow false counts for state-of-the-art semiconductor and electronics UPW systems, onboard tablet interface for modern, multi-functional data analysis
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**CPC UA**



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Wi-Fi is a registered trademark of the Wi-Fi Alliance.



**Knowledge Beyond Measure.**

TSI Incorporated - Visit our website [www.tsi.com](http://www.tsi.com) for more information.

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